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09/903601



Class	Subclass	ISSUE CLASSIFICATION

PATENT NUMBER

U.S. UTILITY Patent Application

O.I.P.E. SCANNED <i>MB</i> <i>CH</i> Q.A. <i>Am</i>	PATENT DATE
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APPLICATION NO. 09/903601	CONT/PRIOR F	CLASS 382	SUBCLASS 145	ART UNIT 2623	EXAMINER <i>J. Marcuso</i>
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APPLICANTS: Ryoichi Matsuoka Virginia Kibler

Semiconductor wafer pattern shape evaluation method and device

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PTO-2040
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ISSUING CLASSIFICATION									
ORIGINAL				CROSS REFERENCE(S)					
CLASS		SUBCLASS		CLASS		SUBCLASS (ONE SUBCLASS PER BLOCK)			
INTERNATIONAL CLASSIFICATION									

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	_____ (Assistant Examiner) _____ (Date)			NOTICE OF ALLOWANCE MAILED	
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